FEATURES

- * Low noise recovery: Ultra soft fast recovery diode.
- * High reverse recovery capability: Super HiRC Structure.
- * High reliability, high durability diodes.
- * Isolated heat sink (terminal to base).

ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item		Symbol	Unit	MDM750H65E2	
Repetitive Peak Reverse Voltage				6,500	
		V _{RRM}	V	6,500	
				6,000	
Forward Current	DC	l _F	Λ	750	
	1ms	I _{FM}	A	1,500	
Junction Temperature		T _{vj op}	°C	-40 ~ +125	
Storage Temperature		T _{stg}	°C	-50 ~ +125	
Isolation Test Voltage	Terminals-base	V_{ISO}	V _{RMS}	10,200(AC 1 minute)	
	Terminal 1-Terminal 2	$V_{ISO T-T}$	V RMS	10,200(AC 1 minute)	
Screw Torque	Terminals (M8)	-	N⋅m	10 (1)	
	Mounting (M6)	-	IN-III	6 (2)	

Notes: (1) Recommended Value 9±1N⋅m

(2) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Тур.	Max.	Test Conditions
Repetitive Reverse Current	I _{RRM}	mΑ	-	10	75	$V_R=6,500V, T_{vj}=150^{\circ}C$
Forward Voltage Dren	\/	V	-	3.8	-	I _F =750A, T _{vj} =25°C
Forward Voltage Drop	V _F		3.75	4.15	4.65	I _F =750A, T _{vj} =125°C
Reverse Recovery Time	t _{rr}	μS	-	0.8	1.6	V _R =3,600V, I _F =750A, L _S =200nH
Payaraa Pagayaru Laga	E _{rr(10%)} J/P		-	2.4		$T_{\text{Vi}}=125^{\circ}\text{C}$, $R_{\text{g}}=8.2\Omega$ (3)
Reverse Recovery Loss	E _{rr(full)}	J/P	-	2.6	-	$1_{\text{V}}=125 \text{ C}, \text{ Rg}=6.2\Omega $ (3)

PACKAGE CHARACTERISTICS

Item	Symbol	Unit	Min.	Тур.	Max.	Test Conditions
Terminal Resistance	R _{CE}	mΩ	-	0.3	-	per arm, T _{vj} =25°C
Stray inductance module	L _{SCE}	nΗ	-	42	-	per arm
Thermal Impedance	R _{th(j-c)}	K/W	-	-	0.017	Junction to case (per arm)
Comparative tracking index	CTI		-	600	-	
Contact Thermal Impedance	R _{th(c-f)}	K/W	-	0.007	-	Case to fin

Notes: (3) Counter arm; MBN750H65E2 VGE=+/-15V

 $R_{\rm G}$ value is the test condition's value for evaluation of the switching times, not recommended value. Please, determine the suitable $R_{\rm G}$ value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.
- * ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2.

DIODE MODULE Spec.No.SR2-SP-09003 R7 P 2

MDM750H65E2

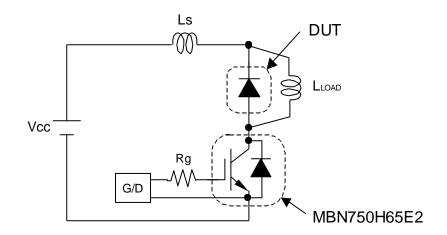


Fig.1 Switching test circuit

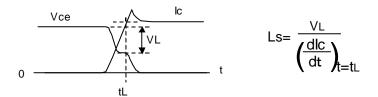


Fig.2 Definition of stray inductance

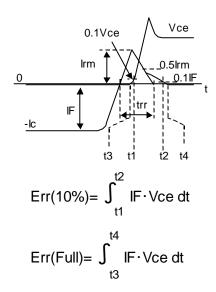
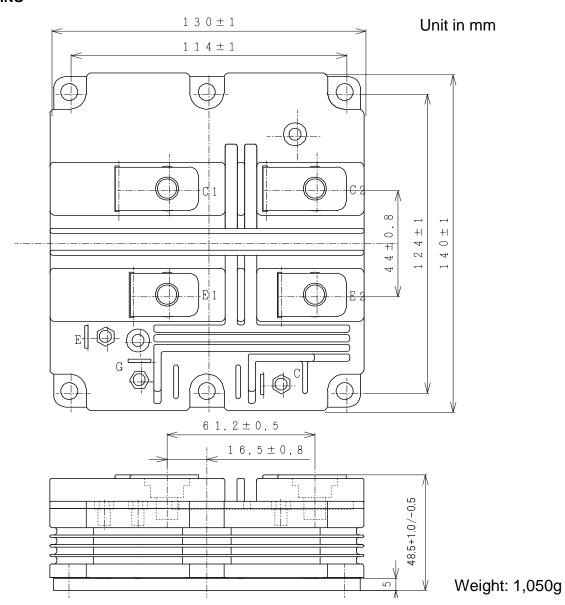
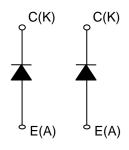


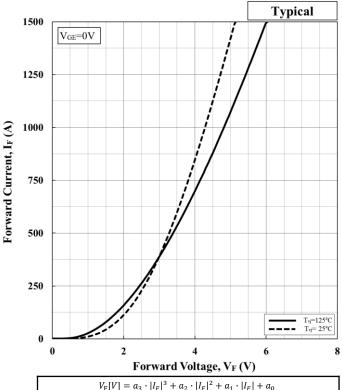
Fig.3 Definition of switching loss

OUTLINE DRAWING



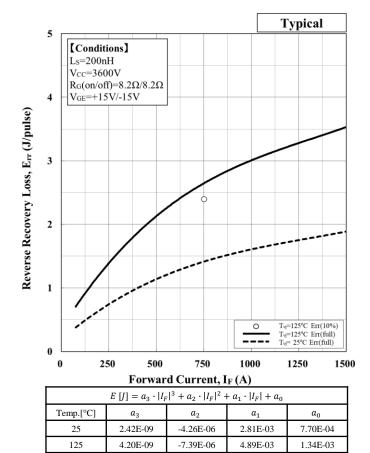
CIRCUIT DIAGRAM



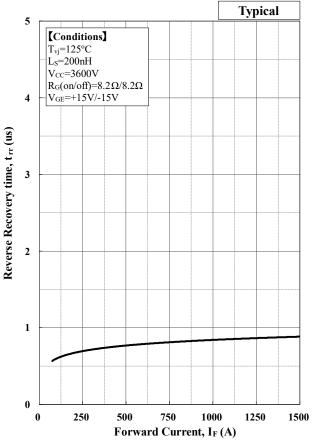


$V_{F}[V] = a_{3} \cdot I_{F} ^{3} + a_{2} \cdot I_{F} ^{2} + a_{1} \cdot I_{F} + a_{0}$					
Temp.[°C]	a_3	a_2	a_1	a_0	
25	8.69E-10	-2.82E-06	4.70E-03	1.53E+00	
125	8.57E-10	-2.94E-06	5.75E-03	1.15E+00	

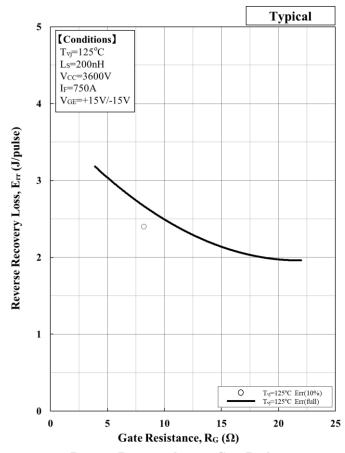
Forward Voltage of diode



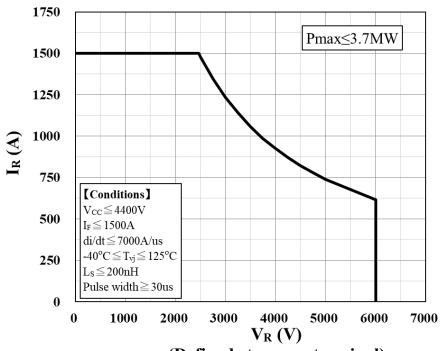
Recovery loss vs. Forward current

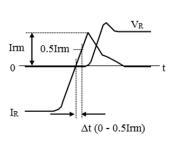


Reverse Recovery time vs. Forward Current



Reverse Recovery loss vs. Gate Resistance

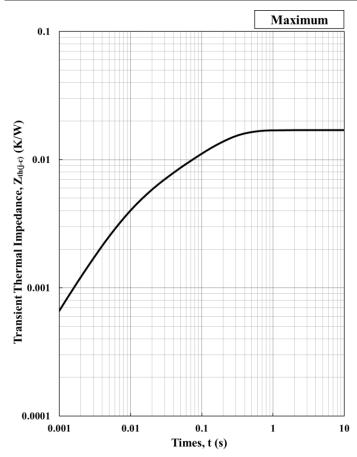




 $di/dt = \frac{0.5Irm}{\Delta t}$

Definition of Recovery di/dt

(Defined at power terminal)
Reverse Recovery Safe Operation Area (RRSOA)



Transient Thermal Impedance Curve

Foster model lumped circuit constant

n	1	2	3	4
R th, Diode [n]	1.06E-02	3.41E-03	2.92E-03	1.00E-04
C th, Diode [n]	1.55E+01	8.07E+00	2.29E+00	7.41E+00

Cauer model lumped circuit constant

n	1	2	3	4
R th, Diode [n]	2.29E-03	3.63E-03	5.27E-03	5.81E-03
C th, Diode [n]	1.32E+00	6.42E-01	6.08E+00	1.71E+01

Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

Minebea POWER SEMICONDUCTORS

Notices

- 1. Since mishandling of semiconductor devices may cause malfunctions, please be sure to read "Precautions for Safe Use and Notices" in the individual brochure before use.
- 2. When designing an electronic circuit using semiconductor devices, please do not exceed the absolute maximum rating specified for the device under any external fluctuations. And for pulse applications, please also do not exceed the "Safe Operating Area (SOA)".
- 3. Semiconductor devices may sometimes break down by accidental or unexpected surge voltage, so please be careful about the safety design such as redundant design and malfunction prevention design which don't cause the damage expand even if they break down.
- 4. In cases where extremely high reliability is required (such as use in nuclear power control, aerospace and aviation, traffic equipment, life-support-related medical equipment, fuel control equipment and various kinds of safety equipment), safety should be ensured by using semiconductor devices that feature assured safety or by means of users' fail-safe precautions or other arrangement. Or consult with MPSD's sales department staff. (When semiconductor devices fail, as a result the semiconductor devices or wiring, wiring pattern may smoke, ignite, or the semiconductor devices themselves may burst.)
- 5. A semi-processed article is done now using solder which contains lead inside the semiconductor devices. There is possibility of the regulation substance depend on the applied models, so please check before using.
- 6. This specification is a material for component selection, which describes specifications of power semiconductor devices (hereinafter referred to as products), characteristic charts, and external dimension drawings.
- 7. The information given herein, including the specifications and dimensions, is subject to change without prior notice to improve product characteristics. Before ordering, purchasers are advised to contact with Minebea power semiconductor sales department for the latest version of this data sheets
- 8. For handling other than described in this manual, follow the handling instructions (IGBT-HI-00002).

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Minebea POWER SEMICONDUCTORS

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